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Title of Invention	SYSTEMS AND METHODS FOR INSPECTION OF SPECIMEN SURFACES						
Application Number:	09/965408						
Confirmation Number:	3796						
First Named Applicant:	Eliezer Rosengaus						
Attorney Docket Number:	5589-02701						
Art Unit:	2877						
Examiner:	Richard A. Rosenberger						
Search string:	(5917588 or 6020957 or 5096291 or 4391524 or 4441124 or 4614427 or 4889998 or 5317380 or 5187596 or 4247203 or 4347001 or 4378159 or 4448532 or 4532650 or 4555798 or 4556317 or 4579455 or 4601576 or 4618938 or 4633504 or 4641967 or 4644172 or 4766324 or 4805123 or 4818110 or 4845558 or 4877326 or 4898471 or 4926489 or 5076692 or 5189481 or 5264912 or 5355212 or 5537669 or 5563702 or 5565979 or 5572598 or 5604585 or 5737072 or 5798829 or 5822055 or 5864394 or 5883710 or 6020214 or 6052478 or 6064517 or 6078386 or						
US Patent Documents							
Note: Applicant is not required to submit a paper copy of cited US Patent Documents							
init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
P	1	5917588	1999-06-29	Addiego			
M	2	6020957	2000-02-01	Rosengaus et al.			
P	3	5096291	1992-03-17	Scott			
M	4	4391524	1983-07-05	Steigmeier et al.			
M	5	4441124	1984-04-03	Heebner et al.			
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Signature

Examiner Name	Date
Richie A) 21	6/25/04

EXAMINER:

DATE CONSIDERED:

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